

Appl. No. 10/527,926  
Amd. Dated February 13, 2007  
Reply to Office Action Dated November 14, 2006

**Amendments to the Specification:**

Please replace the paragraph placed between page 13, line 22 and page 13 line 29 with the following (Paragraph 66):

Taking account of this modification, which may also be applied to probes according to prior art as shown in figure 1 3B, the dimension of the probe may be reduced. This dimension is reduced particularly due to the fact that the means of deploying the potential measurement electrodes are no longer present. Consequently, the probe can be made more compact, such that despite the additional secondary electrodes, the longitudinal length of the probe is hardly longer than a probe according to prior art with the voltage measurement electrodes deployed.

Please replace the paragraph placed between page 13, line 30 and page 14 line 6 with the following (Paragraph 67):

The use of the improved probe comprising a set of secondary electrodes may be the same as that described above in the section on the description of the invention. The probe is moved in steps equal to approximately twice the spacing between consecutive electrodes. At each station, a potential measurement is made after injecting a current using the primary and secondary electrodes. The measurement results obtained from the primary electrodes are used to plot the profile of the variation of the resistivity of the formation shown in FIG. 5A 6A. The ordinate of curve a in FIG. 5A 6A represents the values of the resistivity of the formation in ohm.m, and the abscissa represents the measurement bottom depths.